## Notice of References Cited Application/Control No. 10/814,059 Examiner Luan V. Van Applicant(s)/Patent Under Reexamination KWAK ET AL. Page 1 of 1

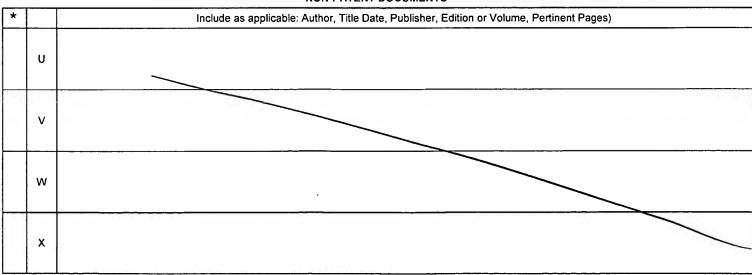
## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2001/0013472	08-2001	Nakamura et al.	205/103
*	В	US-2003/0178315	09-2003	Taylor, E. Jennings	205/103
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
10	Н	US-	/		
	1	US-			
	٦,	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q				7	
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**



\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.